

IN THE SPECIFICATION:

Please amend the paragraph beginning on page 6, line 18, and ending on page 7, line 13, as follows:

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In the case of the optical pickup apparatus 500 described in Japanese Laid-Open Publication No. 9-312033, the semiconductor laser 101 and the light detector 106 are provided on the same stem (or base) 500b. The central dividing line 106c (Figure 7) is substantially perpendicular to a phantom straight line connecting the light emitting point of the semiconductor laser 101 and the focal point of the light on the light detector 106. Since the distance between the semiconductor laser 101 and the light detector 106 changes due to expansion or contraction of the stem 500b when the temperature of the optical pickup apparatus 500 changes, the first order diffracted light component from the diffraction device 105 is shifted toward the light receiving region E or F from the central dividing line 106c of the second light receiver 106b. Thus, the focusing error signal is offset. Since the polarization beam splitter 102 also expands or contracts in accordance with the temperature change, the relative positions of the polarization beam splitter 102 and the mirror 103 change, which also offsets the focusing error signal.
